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Time-Dependent Reliability Analysis for Bivariate Responses

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Outline

- Objective
- Time-dependent System Reliability
- Proposed Method
- Examples
- Conclusions

Objective: Develop a new time-dependent system reliability method for bivariate responses that are general functions of random variables, stochastic processes and time.

Major contribution: Derivation of bivariate joint outcrossing rate.

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Time-Dependent System Reliability

The limit-state function of failure mode i

 $G_i = g_i(\mathbf{X}, \mathbf{Y}(t), t)$

X : random variables; $\mathbf{Y}(t)$: stochastic processes.

Probability of failure

$$p_{f,i}(t_0, t_s) = \Pr\{g_i(\mathbf{X}, \mathbf{Y}(t), t) > e_i, \exists t \in [t_0, t_s]\}$$

 e_i : failure threshold of component *i*



Time-Dependent System Reliability

Let Ω_s be the safe region for a system. For a series system

$$\Omega_s = \left\{ [\mathbf{X}, \mathbf{Y}(t)] \Big| \bigcap_{i=1}^r g_i(\mathbf{X}, \mathbf{Y}(t), t) < e_i, \forall t \in [t_0, t_s] \right\}$$

For a parallel system

$$\boldsymbol{\Omega}_{s} = \left\{ \left[(\mathbf{X}, \mathbf{Y}(t)) \middle| \bigcup_{i=1}^{r} g_{i}(\mathbf{X}, \mathbf{Y}(t), t) < e_{i}, \forall t \in [t_{0}, t_{s}] \right\}$$

The time-dependent system reliability

$$R_s(t_0, t_s) = \Pr\{[\mathbf{X}, \mathbf{Y}(t)] \in \Omega_s, \forall t \in [t_0, t_s]\}$$

Time-Dependent Reliability for Bivariate Responses

Two limit-state functions:

$$G_i = g_i(\mathbf{X}, \mathbf{Y}(t), t)$$
 and $G_j = g_j(\mathbf{X}, \mathbf{Y}(t), t)$

The joint time-dependent P_f

$$p_{f,ij}(t_0, t_s) = \Pr\{g_i(\mathbf{X}, \mathbf{Y}(\chi), \chi) > e_i \cap g_j(\mathbf{X}, \mathbf{Y}(\tau), \tau) > e_j, \exists \chi \text{ and } \tau \in [t_0, t_s]\}$$
$$p_{f,ij}(t_0, t_s) = p_{f,i}(t_0, t_s) + p_{f,j}(t_0, t_s) - p_{f,i \cup j}(t_0, t_s)$$

where

$$p_{f,i\cup j}(t_0,t_s) = \Pr\{g_i(\mathbf{X},\mathbf{Y}(\chi),\chi) > e_i \cup g_j(\mathbf{X},\mathbf{Y}(\tau),\tau) > e_j, \exists \chi \text{ and } \tau \in [t_0,t_s]\}$$

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Part 1: Upcrossing rate method for time-dependent component

$$p_{f,k}(t_0, t_s) = 1 - [1 - p_{f,k}(t_0)] \exp\left\{-\int_{t_0}^{t_s} v_k^+(t) dt\right\}$$

where $v_k^+(t)$ is the upcrossing rate.





Part 2: Joint Probability $p_{f,i\cup j}(t_0,t_s)$

For a series system

$$p_{f,i\cup j}(t_0,t_s) = 1 - R_{ij}(t_0) \exp\left\{-\int_{t_0}^{t_s} v_{i\cup j}^+(t)dt\right\}$$

 $R_{ij}(t_0)$: The probability that both components are safe at t0s $R_{ii}(t_0) = \Pr\{g_i(\mathbf{X}, \mathbf{Y}(t_0), t_0) \le e_i \cap g_i(\mathbf{X}, \mathbf{Y}(t_0), t_0) \le e_i\}$

 $v_{i \cup j}^+(t)$: Outcrossing rate of a series system with components *i* and *j* at time instant *t*





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Joint Outcrossing Rate $v_{i\cup i}^+(t)$ $\Pr\left\{ \begin{bmatrix} G_i(t) < e_i \cap G_j(t) < e_j \end{bmatrix} \\ \cap \left[G_i(t + \Delta t) > e_i \cup G_j(t + \Delta t) > e_j \end{bmatrix} \right\}$ $= p_{ii}^{+-}(t) + p_{ii}^{-+}(t) + p_{ii}^{++}(t)$ $v_{i \cup i}^{+}(t) = v_{ii}^{+-}(t) + v_{ii}^{-+}(t) + v_{ii}^{++}(t)$ $v_{ij}^{+-}(t) = \lim_{\Delta t \to 0} \left(\frac{p_{ij}^{+-}(t)}{\Delta t} \right), v_{ij}^{-+}(t) = \lim_{\Delta t \to 0} \left(\frac{p_{ij}^{-+}(t)}{\Delta t} \right), v_{ij}^{++}(t) = \lim_{\Delta t \to 0} \left(\frac{p_{ij}^{++}(t)}{\Delta t} \right)$

The problem now becomes to calculate the joint uprossing rates



Joint Upcrossing Rates

FORM transforms $(\mathbf{X}, \mathbf{Y}(t))$ into standard normal random variables $\mathbf{U}(t) = (\mathbf{U}_{\mathbf{X}}, \mathbf{U}_{\mathbf{Y}}(t))$. After linearization of the limit-state function at the MPP

With the rice's formula

$$v_{ij}^{+-}(t) = \phi(\beta_{i}(t)) \int_{-\infty}^{\beta_{j}(t)} \frac{\sigma_{L_{i}|L_{i}=\beta_{i}(t), L_{j}=l_{j}}}{\sigma_{L_{j}|L_{i}=\beta_{i}(t)}} \phi\left(\frac{l_{j} - \mu_{L_{j}|L_{i}=\beta_{i}(t)}}{\sigma_{L_{j}|L_{i}=\beta_{i}(t)}}\right) H dl_{j}$$

Where H is a function of reliability indexes and their derivatives



Joint Upcrossing Rates

After obtaining $v_{ij}^{+-}(t)$, $v_{ij}^{-+}(t)$ can be easily obtained by switch the subscripts *i* and *j* for above derived equations.

We proved that when Δt becomes infinitely small

$$v_{ij}^{++}(t) = 0$$

Therefore

$$v_{i\cup j}^{+}(t) = v_{ij}^{+-}(t) + v_{ij}^{-+}(t)$$



Procedures



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A two-bar system

$$g_i(\mathbf{X}, \mathbf{Y}(t), t) = P(t) / 2 - (a_i - 2k_i t)(b_i - 2k_i t)\sigma_{bi}$$

where $\mathbf{X} = [a_1, b_1, a_2, b_2, \sigma_{b1}, \sigma_{b2}], \mathbf{Y}(t) = [P(t)].$

The auto-correlation function of P(t)

$$\rho^{P}(t_{1}, t_{2}) = \exp\left[-\frac{(t_{2} - t_{1})^{2}}{\zeta^{2}}\right], \zeta = 2 \text{ years}$$





Result of Example 1

The curve of outcrossing rate from MCS is not smooth. The noise comes from the numerical discretization of stochastic process.

The error of the new method becomes large with a longer period of time or with a larger probability of failure. The error is mainly from the assumption of independent outcrossings. It is the intrinsic drawback of the outcrossing rate method.

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The results show good accuracy of the proposed method.

θ(°)

80

90

100

110

MCS
New Method





Result of Example 2

The curve of outcrossing rate from MCS is not smooth. The noise comes from the numerical discretization of stochastic process.

The error of the new method becomes large with a longer period of time or with a larger probability of failure. The error is mainly from the assumption of independent outcrossings. It is the intrinsic drawback of the outcrossing rate method.



Conclusions

- A reliability method is proposed for a system with two response variables that are functions of random variables, stochastic processes and time.
- When the dependency between upcrossings are weak, the method has good accuracy.

Future Work

- Improve the accuracy
- Extend the method to systems with multiple responses



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Questions?